

**Search Notes****Application/Control No.**

10/596,849

**Applicant(s)/Patent under  
Reexamination**

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**Examiner**

Sikyln Ip

**Art Unit**

1793

**SEARCHED**

Class	Subclass	Date	Examiner
420	477		
	484	10/13/2009	SI

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
database searched	10/13/2009	SI